

<b>Notice of References Cited</b>	Application/Control No. 10/787,120	Applicant(s)/Patent Under Reexamination TANAKA ET AL.	
	Examiner Chuong A. Luu	Art Unit 2818	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,026,227	04-2006	Tanaka, Koichiro	438/487
*	B	US-2006/0019474	01-2006	Inui et al.	438/487
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	K	US-			
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	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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